

# Xijiang Lin

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/9627197/publications.pdf>

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3  
papers

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citations

3311329

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#	ARTICLE	IF	CITATIONS
1	Single Test Type to Replace Broadside and Skewed-Load Tests for Transition Faults. IEEE Transactions on Very Large Scale Integration (VLSI) Systems, 2021, 29, 423-433.	3.1	1
2	Test Challenges of Intel IA Cores. , 2020, , .		0
3	Test generation for designs with multiple clocks. , 2003, , .		48